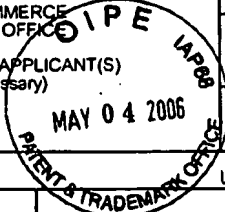


FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 03500.017983.		APPLICATION NO. 10/538,036		
			APPLICANT TADAHIKO HIRAI, et al.				
			FILING DATE June 8, 2005		GROUP 2629		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/A.C./		2002/0195968	12/26/2002	Sanford, et al.	315	169.3	
/A.C./		2003/0016190	01/23/2003	Kondo	345	55	
/A.C./		2003/0052614	03/20/2003	Howard	315	169.1	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/A.C./		1 132 882	03/06/2001	EUROPE			
/A.C./		1 191 512	09/20/2001	EUROPE			
/A.C./		7-013518	01/17/1995	JAPAN			Abstract
/A.C./		5-094150	04/16/1993	JAPAN			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
/A.C./		J. H. Wei, et al., "Improved stability of deuterated amorphous silicon thin film transistors", <i>Journal Of Applied Physics</i> , vol. 85, No. 1, pp, 543-550, (January 1, 1999).					
		H. Hamada, "Sharp Technical Report", No. 69 (1997), p. 75.					
EXAMINER				DATE CONSIDERED			
/Afroza Chowdhury/				09/18/2007			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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